

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

SERIAL NO.

550-235

09/876,220

APPLICANT

SWAINE

FILING DATE

GROUP

June 8, 2001

2183

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BB	5,802,273	9/1998	Levine et al.			
	4,590,550	5/1986	Eilert			
	4,821,178	4/1989	Levin et al.			
	5,151,981	9/1992	Westcott et al.			
	5,347,647	9/1994	Allt et al.			
	5,550,974	8/1996	Pennington et al.			
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	5,923,872	7/1999	Chrysos et al.			
	5,978,742	11/1999	Pickerd			
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	6,067,644	5/2000	Levine et al.			
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DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
BB	0 465 765	1/1992	EP		
BB	0 689 141	12/1995	EP		
BB	0 919 919	6/1999	EP		

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

BB	ARM966E-S Technical Reference Manual, 12/1999, Arm Limited, Issue A, Chapter 1.
	Embedded Trace Macrocell Architecture Specification, 12/2002, Arm Limited, Issue 1, Chapters 1 and 2 and Appendix B.
	Uhlig et al., Trace-Driven Memory Simulation: A Survey, 6/1997, ACM Computing Surveys, Vol. 29, No. 2, pages 128-170.
	ARM IHI 0014 Revision C - Embedded Trace Macrocell Specification.
	ARM DDI 0157F - ETM9 (Rev. 1) Technical Reference Manual
	ARM DDI 0158D-ETM7 (Rev. 1) Technical Reference Manual.
	U.S. application serial number 09/773,387, filed February 1, 2001.
BB	ARM IHI 0014 Revision I-Embedded Trace Macrocell Spec.

*Examiner

Date Considered

2/9/05

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

EXAMINER
INITIALS
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FOREIGN PATENT DOCUMENTS

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OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

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